

CY62148E MoBL[®]

4-Mbit (512 K × 8) Static RAM

Features

- Very high speed: 45 ns
- Voltage range: 4.5 V to 5.5 V
- Pin compatible with CY62148B
- Ultra low standby power
 □ Typical standby current: 1 µA
 □ Maximum standby current: 7 µA (Industrial)
- Ultra low active power
 Typical active current: 2.0 mA at f = 1 MHz
- Easy memory expansion with CE, and OE features
- Automatic power-down when deselected
- Complementary metal oxide semiconductor (CMOS) for optimum speed and power
- Available in Pb-free 32-pin thin small outline package (TSOP) II and 32-pin small-outline integrated circuit (SOIC)^[1] packages

Functional Description

The CY62148E is a high performance CMOS static RAM organized as 512 K words by 8-bits. This device features

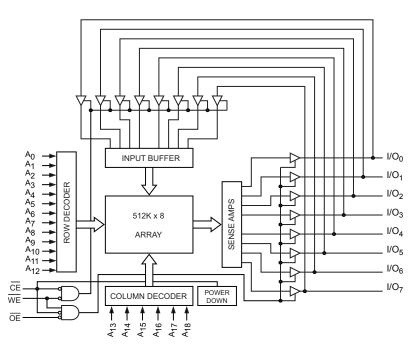
Logic Block Diagram

advanced circuit design to provide ultra low standby current. This is ideal for providing More Battery LifeTM (MoBL[®]) in portable applications. The device also has an automatic power-down feature that significantly reduces power consumption when addresses are not toggling. Placing the device into standby mode reduces power consumption by more than 99% when deselected (CE HIGH). The eight input and output pins (I/O₀ through I/O₇) are placed in a high impedance state when the device is deselected (CE HIGH), Outputs are disabled (OE HIGH), or during an active Write operation (CE LOW and WE LOW).

<u>To write</u> to the device, take Chip Enable (\overline{CE}) and Write Enable (\overline{WE}) inputs LOW. Data on the eight I/O pins (I/O₀ through I/O₇) is then written into the location specified on the address pins (A₀ through A₁₈).

To read <u>from</u> the device, take Chip Enable (\overline{CE}) and Output Enable (\overline{OE}) LOW while forcing Write Enable (WE) HIGH. Under these conditions, the contents of the memory location specified by the address pins appear on the I/O pins.

The CY62148E device is suitable for interfacing with processors that have TTL I/P levels. It is not suitable for processors that require CMOS I/P levels. Please see Electrical Characteristics on page 4 for more details and suggested alternatives.



Note

1. SOIC package is available only in 55 ns speed bin.

Cypress Semiconductor Corporation Document Number: 38-05442 Rev. *L 198 Champion Court

San Jose, CA 95134-1709



CY62148E MoBL[®]

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Pin Configurations

Figure 1. 32-pin SOIC/TSOP II pinout

Top View

A17 E	1	32 VCC
А ₁₆ Г	2	31 A15
A ₁₄ Г	3	₃₀ _ A ₁₈
А ₁₂ Г	4	29 🗆 WE
Α7 Γ	5	28 A A13
	6	27 🗖 A ₈
A ₅ –	7	26 A9
A4 E	8	25 🗖 A ₁₁
A3 E	q	24 🗆 OE
A ₂ –	10	23 🗖 A ₁₀
A1 T	11	22 🗆 CE
	12	21 🛛 I/O7
	13	20 🛛 I/O ₆
	14	19 🗆 I/O ₅
1/O ₂	15	18 🛛 I/O4
V _{SS} E	16	17 🛛 I/O ₃

Product Portfolio

					Power Dissipation										
Product		Product			V _{CC} Range (V)		V _{CC} Range (V)		Speed	O	perating	g I _{CC} (mA	N)	Standby	L (11 A)
FIGUU	,L		(ns) f = 1				f = 1 MHz		max	– Standby I _{SB2} (µA)					
		Range	Min	Typ ^[2]	Max		Тур [2]	Max	Typ ^[2]	Max	Typ ^[2]	Мах			
CY62148ELL	TSOP II	Industrial	4.5	5.0	5.5	45	2	2.5	15	20	1	7			
CY62148ELL	SOIC	Industrial / Automotive-A	4.5	5.0	5.5	55	2	2.5	15	20	1	7			



Maximum Ratings

Exceeding maximum ratings may shorten the useful life of the device. User guidelines are not tested.

Storage temperature65 °C to + 150 °C
Ambient temperature with power applied55 °C to + 125 °C
Supply voltage to ground potential0.5 V to 6.0 V (V _{CCmax} + 0.5 V)
DC voltage applied to outputs in high Z state $^{[3,\ 4]}$ 0.5 V to 6.0 V (V $_{CCmax}$ + 0.5 V)

DC input voltage $^{[3, 4]}$ –0.5 V to 6.0 V (V _C	_{Cmax} + 0.5 V)
Output current into outputs (LOW)	20 mA
Static discharge voltage (per MIL-STD-883, Method 3015)	> 2001 V
Latch-up current	> 200 mA

Operating Range

Device	Range	Ambient Temperature	V_{CC} ^[5]
CY62148E	Industrial / Automotive-A	–40 °C to +85 °C	4.5 V to 5.5 V

Electrical Characteristics

Over the operating range

Deremeter	Description	Test Con	ditiono		45 n	s		55 ns	[6]	Unit
Parameter	Description	Test Con			Typ ^[7]	Max	Min	Typ ^[7]	Max	Unit
V _{OH} ^[8]	Output HIGH voltage	V _{CC} = 4.5 V, I _{OH} = -	-1 mA	2.4	-	-	2.4	-	-	V
		V _{CC} = 5.5 V, I _{OH} = -	-0.1 mA	_	_	3.4 ^[8]	-	_	3.4 ^[8]	V
V _{OL}	Output LOW voltage	I _{OL} = 2.1 mA		—	_	0.4	-	-	0.4	V
V _{IH}	Input HIGH voltage	V _{CC} = 4.5 V to 5.5 V	/	2.2	_	V _{CC} + 0.5	2.2	_	V _{CC} + 0.5	V
V _{IL}	Input LOW voltage	$V_{\rm CC}$ = 4.5 V to 5.5 V	For TSOPII package	-0.5	-	0.8	-	-	-	V
			For SOIC package	_	-	-	-0.5	-	0.6 ^[9]	
I _{IX}	Input leakage current	$GND \leq V_1 \leq V_{CC}$		-1	_	+1	-1	_	+1	μA
I _{OZ}	Output leakage current	$GND \leq V_O \leq V_{CC}$, ou	tput disabled	-1	_	+1	-1	_	+1	μA
I _{CC}	V _{CC} operating supply	$f = f_{max} = 1/t_{RC}$	$V_{CC} = V_{CC(max)},$	_	15	20	-	15	20	mA
	current	f = 1 MHz	I _{OUT} = 0 mA CMOS levels	_	2	2.5	-	2	2.5	
I _{SB2} ^[10]	Automatic CE power-down current – CMOS inputs	$\begin{array}{l} \hline CE \geq V_{CC} - 0.2 \text{ V}, \\ V_{IN} \geq V_{CC} - 0.2 \text{ V or } V_{IN} \leq 0.2 \text{ V}, \\ f = 0, V_{CC} = V_{CC(max)} \end{array}$		_	1	7	_	1	7	μA

Notes

- 3. $V_{IL(min)} = -2.0 \text{ V}$ for pulse durations less than 20 ns for I \leq 30 mA. 4. $V_{IH(max)} = V_{CC} + 0.75 \text{ V}$ for pulse durations less than 20 ns. 5. Full device AC operation assumes a minimum of 100 µs ramp time from 0 to $V_{CC(min)}$ and 200 µs wait time after V_{CC} stabilization.
- 6. SOIC package is available only in 55 ns speed bin.

- SOIC package is available only in 55 ns speed bin.
 Typical values are included for reference and are not guaranteed or tested. Typical values are measured at V_{CC} = V_{CC(typ)}, T_A = 25 °C.
 Please note that the maximum V_{OH} limit for this device does not exceed minimum CMOS V_{IH} of 3.5V. If you are interfacing this SRAM with 5 V legacy processors that require a minimumV_{IH} of 3.5 V, please refer to Application Note AN6081 for technical details and options you may consider.
 Under DC conditions the device meets a V_{IL} of 0.8 V. However, in dynamic conditions Input LOW Voltage applied to the device must not be higher than 0.6 V. This is applicable to SOIC package only.
 Chip enable (CE) must be HIGH at CMOS level to meet the I_{SB2} / I_{CCDR} spec. Other inputs can be left floating.



Capacitance

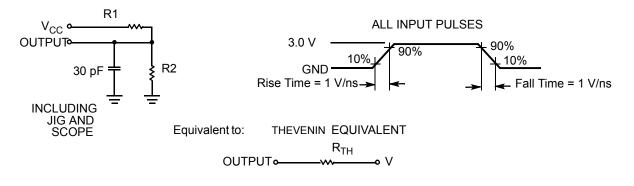
Parameter [11]	Description	Test Conditions	Мах	Unit
C _{IN}	Input capacitance	$T_A = 25 \text{ °C}, f = 1 \text{ MHz}, V_{CC} = V_{CC(Typ)}$	10	pF
C _{OUT}	Output capacitance		10	pF

Thermal Resistance

Parameter [11]	Description	Test Conditions	32-pin SOIC Package	32-pin TSOP II Package	Unit
Θ_{JA}		Still air, soldered on a 3 × 4.5 inch, two-layer printed circuit board	75	77	°C/W
Θ _{JC}	Thermal resistance (junction to case)		10	13	°C/W

AC Test Loads and Waveforms





Parameter [11]	5.0 V	Unit
R1	1800	Ω
R2	990	Ω
R _{TH}	639	Ω
V _{TH}	1.77	V



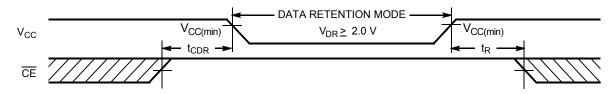
Data Retention Characteristics

Over the operating range

Parameter	Description	Conditio	Conditions		Typ ^[12]	Max	Unit
V _{DR}	V _{CC} for data retention			2	-	-	V
I _{CCDR} ^[13]	Data retention current	$V_{CC} = V_{DR},$ $\overline{CE} \ge V_{CC} - 0.2 V,$ $V_{IN} \ge V_{CC} - 0.2 V \text{ or }$ $V_{IN} \le 0.2 V$	Industrial / Automotive-A	_	1	7	μA
t _{CDR}	Chip deselect to data retention time			0	-	-	ns
t _R ^[14]	Operation recovery time		TSOP II	45	-	-	ns
			SOIC	55	_	_	ns

Data Retention Waveform





Notes

- 12. Typical values are included for reference and are not guaranteed or tested. Typical values are measured at $V_{CC} = V_{CC(typ)}$, $T_A = 25 °C$. 13. Chip enable (CE) must be HIGH at CMOS level to meet the I_{SB2} / I_{CCDR} spec. Other inputs can be left floating. 14. Full device operation requires linear V_{CC} ramp from V_{DR} to $V_{CC(min)} > 100 \ \mu s$ or stable at $V_{CC(min)} > 100 \ \mu s$.



Switching Characteristics

Over the operating range

Parameter [15]	Description	45	ns	55 ns ^[16]		11
Parameter	Description	Min	Max	Min	Max	- Unit
Read Cycle						•
t _{RC}	Read cycle time	45	_	55	_	ns
t _{AA}	Address to data valid	-	45	-	55	ns
t _{OHA}	Data hold from address change	10	-	10	-	ns
t _{ACE}	CE LOW to data valid	-	45	-	55	ns
t _{DOE}	OE LOW to data valid	-	22	-	25	ns
t _{LZOE}	OE LOW to low Z ^[17]	5	-	5	-	ns
t _{HZOE}	OE HIGH to high Z ^[17, 18]	-	18	-	20	ns
t _{LZCE}	CE LOW to low Z ^[17]	10	-	10	-	ns
t _{HZCE}	CE HIGH to high Z [17, 18]	-	18	-	20	ns
t _{PU}	CE LOW to power-up	0	-	0	-	ns
t _{PD}	CE HIGH to power-down	-	45	-	55	ns
Write Cycle [19]	1					•
t _{WC}	Write cycle time	45	-	55	-	ns
t _{SCE}	CE LOW to write end	35	-	40	-	ns
t _{AW}	Address setup to write end	35	-	40	-	ns
t _{HA}	Address hold from write end	0	-	0	-	ns
t _{SA}	Address setup to write start	0	-	0	-	ns
t _{PWE}	WE pulse width	35	-	40	-	ns
t _{SD}	Data setup to write end	25	-	25	-	ns
t _{HD}	Data hold from write end	0	-	0	-	ns
t _{HZWE}	WE LOW to high Z ^[17, 18]	-	18	-	20	ns
t _{LZWE}	WE HIGH to low Z ^[17]	10	-	10	-	ns

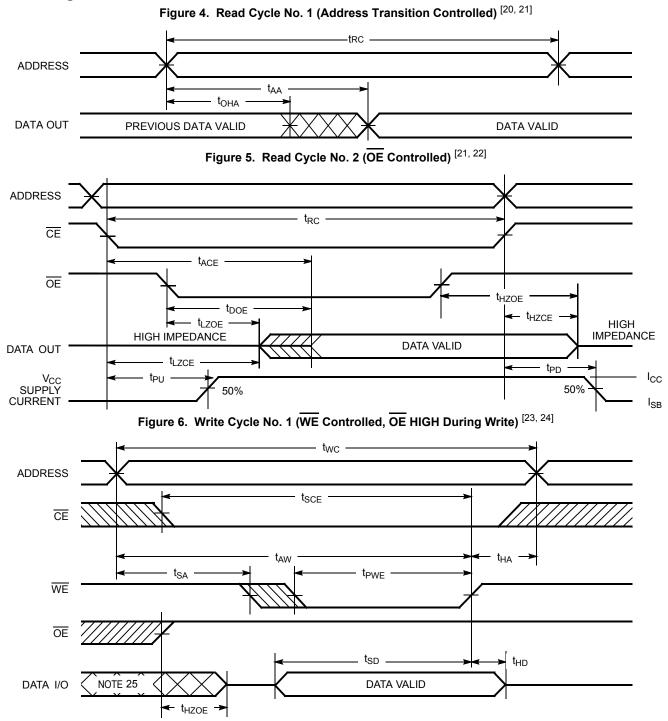
Notes

17. At any temperature and voltage condition, t_{HZCE} is less than t_{LZCE}, t_{HZOE} is less than t_{LZCE}, and t_{HZWE} is less than t_{LZWE} for any device.
18. t_{HZOE}, t_{HZCE}, and t_{HZWE} transitions are measured when the outputs enter a high impedance state.
19. The internal wre ite time of the memory is defined by the overlap of WE, CE = V_{IL}. All signals must be ACTIVE to initiate a write and any of these signals can terminate a write by going INACTIVE. The data input setup and hold timing should be referenced to the edge of the signal that terminates the write.

Test conditions for all parameters other than tri-state parameters assume signal transition time of 3 ns or less, timing reference levels of 1.5 V, input pulse levels of 0 to 3 V, and output loading of the specified I_{OL}/I_{OH} as shown in the Figure 2 on page 5.
 SOIC package is available only in 55 ns speed bin.



Switching Waveforms



Notes

- 20. Device is continuously selected. OE, CE = V_{IL}.

 21. WE is HIGH for read cycles.

 22. Address valid before or similar to CE transition LOW.

 23. Data I/O is high impedance if OE = V_{IL}.

 24. If CE goes HIGH simultaneously with WE HIGH, the output remains in high impedance state.

 25. During this period, the I/Os are in output state and input signals must not be applied.



Switching Waveforms (continued)

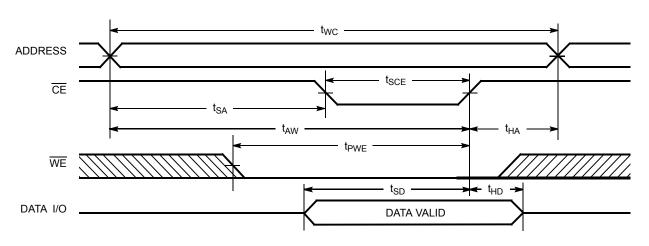
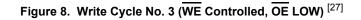
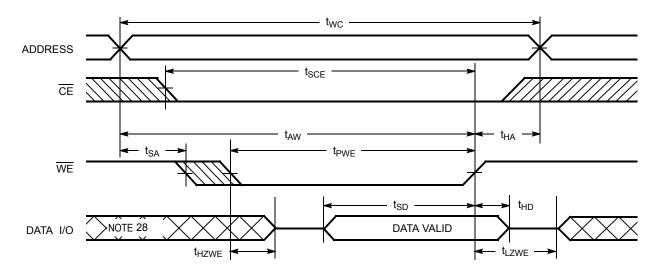


Figure 7. Write Cycle No. 2 (CE Controlled) ^[26, 27]





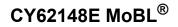
Notes

26. Data I/O is high impedance if $\overline{OE} = V_{IH.}$ 27. If CE goes HIGH simultaneously with WE HIGH, the output remains in high impedance state. 28. During this period, the I/Os are in output state and input signals must not be applied.



Truth Table

CE	WE	OE	I/O	Mode	Power
H ^[29]	Х	Х	High Z	Deselect/power-down	Standby (I _{SB})
L	Н	L	Data out	Read	Active (I _{CC})
L	L	Х	Data in	Write	Active (I _{CC})
L	Н	Н	High Z	Selected, outputs disabled	Active (I _{CC})





Ordering Information

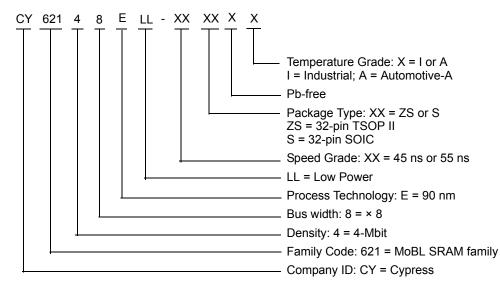
Table 1 lists the CY62148E MoBL[®] key package features and ordering codes. The table contains only the parts that are currently available. If you do not see what you are looking for, contact your local sales representative. For more information, visit the Cypress website at www.cypress.com and refer to the product summary page at http://www.cypress.com/products.

Table 1.	Key features	and Ordering	Information
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Speed (ns)	Ordering Code	Package Diagram	Package Type	Operating Range
45	CY62148ELL-45ZSXI	51-85095	32-pin TSOP II (Pb-free)	Industrial
	CY62148ELL-45ZSXA	51-85095	32-pin TSOP II (Pb-free)	Automotive-A
55	CY62148ELL-55SXI	51-85081	32-pin SOIC (Pb-free)	Industrial
	CY62148ELL-55SXA	51-85081	32-pin SOIC (Pb-free)	Automotive-A

Contact your local Cypress sales representative for availability of these parts.

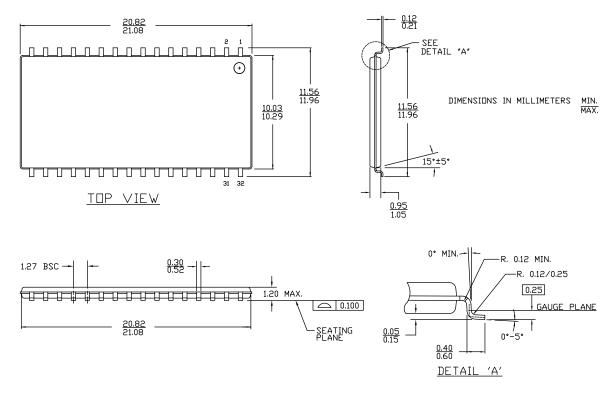
Ordering Code Definitions





Package Diagrams

Figure 9. 32-pin TSOP II (20.95 × 11.76 × 1.0 mm) ZS32 Package Outline, 51-85095

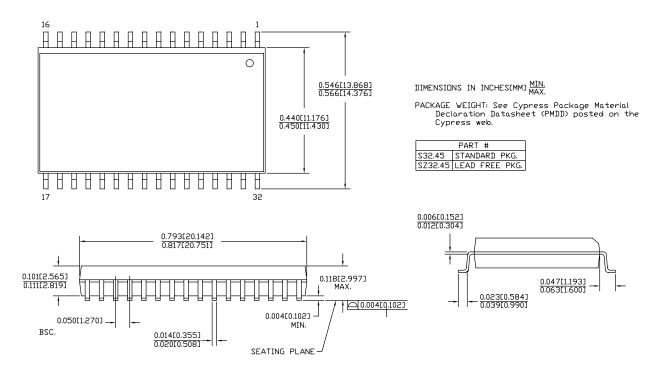


51-85095 *B



Package Diagrams (continued)





51-85081 *E





Acronyms

Acronym	Description			
CE	Chip Enable			
CMOS	Complementary Metal Oxide Semiconductor			
I/O	Input/Output			
OE	Output Enable			
MoBL	More Battery Life			
SOIC	Small Outline Integrated Circuit			
SRAM	Static Random Access Memory			
TSOP	Thin Small Outline Package			
WE	Write Enable			

Document Conventions

Units of Measure

Symbol	Unit of Measure
°C	degree Celsius
MHz	megahertz
μA	microampere
μs	microsecond
mA	milliampere
ns	nanosecond
Ω	ohm
%	percent
pF	picofarad
V	volt
W	watt





Document History Page

Revision	ECN	Orig. of Change	Submission Date	Description of Change
**	201580	AJU	01/08/04	New data sheet.
*A	249276	SYT	See ECN	Changed status from Advance Information to Preliminary. Updated Features (Added RTSOP II and removed FBGA Package). Updated Functional Description (Added RTSOP II and removed FBGA Package) UpdatedPin Configurations (Added RTSOP II and removed FBGA Package). Updated Operating Range (Updated Note 5 (Changed V _{CC} stabilization time from 100 μ s to 200 μ s)). Updated Data Retention Characteristics (Changed maximum value of I _{CCDF} parameter from 2.0 μ A to 2.5 μ A, changed minimum value of t _R parameter from 100 μ s to t _{RC} ns). Updated Switching Characteristics (Changed minimum value of t _{OHA} parameter from 6 ns to 10 ns for both 35 ns and 45 ns speed bin, changed maximum value of t _{DOE} parameter from 15 ns to 18 ns for 35 ns speed bin, changed maximum value of t _{HZOE} , t _{HZWE} parameters from 12 ns to 15 ns for 35 ns speed bin and 15 ns to 18 ns for 45 ns speed bin, changed minimum value of t _{SCE} parameter from 25 ns to 30 ns for 35 ns speed bin and 40 ns to 35 ns for 45 ns speed bin changed maximum value of t _{HZCE} parameter from 12 ns to18 ns for 35 ns speed bin changed maximum value of t _{HZCE} parameter from 12 ns to18 ns for 35 ns speed bin and 15 ns to 22 ns for 45 ns speed bin, changed minimum value of t _{SCE} parameter from 15 ns to 18 ns for 35 ns speed bin, changed minimum value of t _{SI}
B*	414820	ZSD	See ECN	Changed status from Preliminary to Final Changed the address of Cypress Semiconductor Corporation on Page #1 fror "3901 North First Street" to "198 Champion Court" Updated Features (Removed 35 ns speed bin). Updated Pin Configurations (Removed the Note "DNU pins have to be left floatin or tied to V _{SS} to ensure proper application." and its reference). Updated Product Portfolio (Removed 35 ns speed bin). Updated Maximum Ratings (Updated Note 3 to include current limit). Updated Electrical Characteristics (Removed "L" version of CY62148E, change typical value of I _{CC} parameter from 1.5 mA to 2 mA at f = 1 MHz, changed maximur value of I _{CC} parameter from 2 mA to 2.5 mA at f = 1 MHz, changed typical valu of I _{CC} parameter from 12 mA to 15 mA at f = f _{max} , removed I _{SB1} parameter and it details, changed typical value of I _{SB2} parameter from 0.7 µA to 1 µA and maximur value of I _{SB2} parameter from 2.5 µA to 7 µA). Updated AC Test Loads and Waveforms (Changed the AC test load capacitanc from 100 pF to 30 pF in Figure 2, changed test load parameters R ₁ , R ₂ , R _{TH} an V _{TH} from 1838 Ω , 994 Ω , 645 Ω and 1.75 V to 1800 Ω , 990 Ω , 639 Ω and 1.77 V Updated Data Retention Characteristics (Changed maximum value of I _{CCD} parameter from 2.5 µA to 7 µA, Added typical value for I _{CCDR} parameter). Updated Switching Characteristics (Removed 35 ns speed bin, changed minimur value of t _{LZOE} parameter from 3 ns to 5 ns, changed minimum value of t _{LZCE} an t _{LZWE} parameters from 6 ns to 10 ns, changed maximum value of t _{LZCE} parameter from 22 ns to 18 ns, changed minimum value of t _{PWE} parameter from 30 ns t 35 ns, changed minimum value of t _{SD} parameter from 22 ns to 25 ns). Updated Ordering Information (Updated ordering codes and replaced Packag Name column with Package Diagram).



Document History Page (continued)

Documer Documer	nt Number:	1	Orthand	
Revision	ECN	Orig. of Change	Submission Date	Description of Change
*C	464503	NXR	See ECN	Updated Product Portfolio (Included Automotive Range). Updated Operating Range (Included Automotive Range). Updated Electrical Characteristics (Included Automotive Range). Updated Data Retention Characteristics (Included Automotive Range). Updated Switching Characteristics (Included Automotive Range). Updated Ordering Information (Updated ordering codes (Included Automotive parts and their related information)).
*D	485639	VKN	See ECN	Updated Operating Range (Updated V _{CC} to 4.5 V to 5.5 V).
*E	833080	VKN	See ECN	Updated Electrical Characteristics (Added V_{IL} parameter for SOIC package, added Note 9 and referred the same note in V_{IL} parameter for SOIC package).
*F	890962	VKN	See ECN	Updated Pin Configurations (Added Note 1 related to SOIC package). Updated Product Portfolio (Included Automotive-A range and removed Automotive-E range). Updated Operating Range (Included Automotive-A range and removed Automotive-E range). Updated Electrical Characteristics (Included Automotive-A range and removed Automotive-E range, added Note 10 related to I _{SB2} and referred the same note in I _{SB2} parameter). Updated Data Retention Characteristics (Included Automotive-A range and removed Automotive-E range). Updated Data Retention Characteristics (Included Automotive-A range and removed Automotive-E range). Updated Switching Characteristics (Included Automotive-A range and removed Automotive-E range). Updated Ordering Information (Updated ordering codes (Added Automotive-A part and its related information, removed Automotive-E part and its related information).
*G	2947039	VKN	06/10/2010	Updated Truth Table (Added Note 29 and referred the same note in CE column). Updated Ordering Information (Added "CY62148ELL-45ZSXA" part number). Updated Package Diagrams. Added Sales, Solutions, and Legal Information.
*H	3006318	AJU	08/23/10	Updated Data Retention Characteristics (Added note 13 and referred the same note in I _{CCDR} parameter). Added Ordering Code Definitions. Added Acronyms and Units of Measure. Updated in new template.
*	3235744	RAME	04/20/2011	Updated Functional Description (Removed the line "For best practice recommendations, refer to the Cypress application note AN1064, SRAM System Guidelines"). Updated Package Diagrams.
*J	3302815	RAME	07/14/2011	Updated in new template.
*K	3539544	TAVA	03/01/2012	Updated Electrical Characteristics (Updated Note 9). Updated Package Diagrams.
*L	3992135	MEMJ	05/06/2013	Updated Functional Description. Updated Electrical Characteristics (Added one more Test Condition " $V_{CC} = 5.5 \text{ V}$, $I_{OH} = -0.1 \text{ mA}$ " for V_{OH} parameter and its corresponding values). Updated Package Diagrams: spec 51-85081 – Changed revision from *D to *E. Completing Sunset Review.



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